Features

Low-voltage and Standard-voltage Operation

- V_{CC} = 1.7V to 5.5V

- Internally Organized 256 x 8 (2K)
- Two-wire Serial Interface
- Schmitt Trigger, Filtered Inputs for Noise Suppression
- Bidirectional Data Transfer Protocol
- 1 MHz (5V), 400 kHz (1.7V, 2.5V, 2.7V) Compatibility
- Write Protect Pin for Hardware Data Protection
- 8-byte Page (2K) Write Modes
- Partial Page Writes Allowed
- Self-timed Write Cycle (5 ms max)
- High-reliability
 - Endurance: 1 Million Write Cycles
 - Data Retention: 100 Years
- Green (Pb/Halide-free/RoHS Compliant) Package Options
- Die Sales: Wafer Form and Tape and Reel

Die Configuration

Description

The AT24C02C provides 2048 bits of serial electrically erasable and programmable read-only memory (EEPROM) organized as 256 words of 8 bits each. The device is optimized for use in many industrial and commercial applications where low-power and low-voltage operation are essential. The AT24C02C is available in space-saving 8-lead PDIP, 8-lead JEDEC SOIC, 8-lead UDFN, 5-lead SOT23, 8-lead TSSOP, and 8-ball VFBGA packages and is accessed via a Two-wire serial interface.

Table 0-1.	Pin Configuration
Pin Name	Function
A0 - A2	Address Inputs
SDA	Serial Data
SCL	Serial Clock Input
WP	Write Protect
GND	Ground
VCC	Power Supply

Note: For use of 5-lead SOT23, the software A2, A1, and A0 bits in the device address word must be set to zero to properly communicate.

8-l	ead	UDI	FN
VCC	8	1	A0
WP	7	2	A1
SCL	6	3	A2
SDA	5	4	GND
Bo	otton	n Vie	W

8-le	ad TS	s	OP
A0 🗆	$1 \bigcirc$	8	
A1 🗆	2	7	🗆 WP
A2 🗆	3	6	🗆 SCL
GND 🗆	4	5	🗆 SDA

5-le	ead SC)T	23
SCL	1	5	WP
GND	2		
	3	4	

8-ball VFBGA					
VCC WP SCL SDA	8	1	A0 A1 A2 GND		
WP	7	2	A1		
SCL	6	3	A2		
SDA	5	4	GND		
Bottom View					
8-lead SOIC					

A0 🗔	1	8	
A1 🗔	2	7	🗆 WP
A2 🗔	3	6	SCL
GND 🗔	4	5	🗀 SDA

8-lead PDIP				
A0 🗆	1	\cup	8	Dov 🗆
A1 🗆	2		7	□ WP
A2 🗆	3		6	SCL
GND 🗆	4		5	🗆 SDA



Two-wire Serial EEPROM

2K (256 x 8)

AT24C02C Preliminary

8700B-DEEPR-2/10



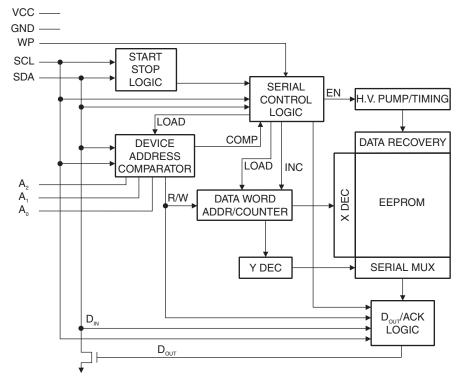


Absolute Maximum Ratings

Operating Temperature55°C to +125°C
Storage Temperature65°C to +150°C
Voltage on Any Pin with Respect to Ground1.0V to +7.0V
Maximum Operating Voltage 6.25V
DC Output Current 5.0 mA

Figure 0-1. Block Diagram

*NOTICE: Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



1. Pin Description

SERIAL CLOCK (SCL): The SCL input is used to positive edge clock data into each EEPROM device and negative edge clock data out of each device.

SERIAL DATA (SDA): The SDA pin is bidirectional for serial data transfer. This pin is opendrain driven and may be wire-ORed with any number of other open-drain or open-collector devices.

DEVICE/PAGE ADDRESSES (A2, A1, A0): The A2, A1 and A0 pins are device address inputs that are hard wired for the AT24C02C. As many as eight 2K devices may be addressed on a single bus system (device addressing is discussed in detail under the Device Addressing section).

WRITE PROTECT (WP): The AT24C02C has a write protect pin that provides hardware data protection. The write protect pin allows normal read/write operations when connected to ground

² AT24C02C [Preliminary]

(GND). When the write protect pin is connected to V_{CC} , the write protection feature is enabled and operates as shown in Table 1-1.

WP Pin Status	Part of the Array Protected	
	24C02C	
At V _{CC}	Full (2K) Array	
At GND	Normal Read/Write Operations	

Table 1-1. Write Protect

2. Memory Organization

AT24C02C, 2K SERIAL EEPROM: Internally organized with 32 pages of 8 bytes each, the 2K requires an 8-bit data word address for random word addressing.





Table 2-1.Pin Capacitance⁽¹⁾

Applicable over recommended operating range from $T_A = 25^{\circ}C$, f = 1.0 MHz, $V_{CC} = +1.7V$ to +5.5V

Symbol	Test Condition	Мах	Units	Conditions
C _{I/O}	Input/Output Capacitance (SDA)	8	pF	$V_{I/O} = 0V$
C _{IN}	Input Capacitance (A ₀ , A ₁ , A ₂ , SCL)	6	pF	$V_{IN} = 0V$

Note: 1. This parameter is characterized and is not 100% tested.

Table 2-2.DC Characteristics

A multipadala, ay yay ya a amana a mala al a mayatin	$\sim 100 \text{ C} \text{ to } 100 \text{ C}$	(1, 7)/(1 + 1) = (1, 7)/(1 + 1) = (1, 1)/(1 + 1)
Applicable over recommended operatin	g range from: $I_{AI} = -40^{\circ}$ C to $+85^{\circ}$ C, V_{C}	$_{CC}$ = +1.7V to +5.5V (unless otherwise noted)

Symbol	Parameter	Test Condition	Min	Тур	Max	Units
V _{CC1}	Supply Voltage		1.7		5.5	V
V _{CC2}	Supply Voltage		2.5		5.5	V
V _{CC3}	Supply Voltage		2.7		5.5	V
V _{CC4}	Supply Voltage		4.5		5.5	V
I _{CC}	Supply Current V _{CC} = 5.0V	READ at 100 kHz		0.4	1.0	mA
I _{CC}	Supply Current V _{CC} = 5.0V	WRITE at 100 kHz		2.0	3.0	mA
I _{SB1}	Standby Current V _{CC} = 1.7V	$V_{IN} = V_{CC} \text{ or } V_{SS}$		0.6	3.0	μA
I _{SB2}	Standby Current $V_{CC} = 2.5V$	$V_{IN} = V_{CC} \text{ or } V_{SS}$		1.4	4.0	μA
I _{SB3}	Standby Current V _{CC} = 2.7V	$V_{IN} = V_{CC} \text{ or } V_{SS}$		1.6	4.0	μA
I _{SB4}	Standby Current $V_{CC} = 5.0V$	$V_{IN} = V_{CC} \text{ or } V_{SS}$		8.0	18.0	μA
ILI	Input Leakage Current	$V_{IN} = V_{CC} \text{ or } V_{SS}$		0.10	3.0	μA
I _{LO}	Output Leakage Current	$V_{OUT} = V_{CC} \text{ or } V_{SS}$		0.05	3.0	μA
V _{IL}	Input Low Level ⁽¹⁾		-0.6		V _{CC} x 0.3	V
V _{IH}	Input High Level ⁽¹⁾		V _{CC} x 0.7		V _{CC} + 0.5	V
V _{OL2}	Output Low Level V _{CC} = 3.0V	I _{OL} = 2.1 mA			0.4	V
V _{OL1}	Output Low Level V _{CC} = 1.7V	I _{OL} = 0.15 mA			0.2	V

Table 2-3.AC Characteristics

Applicable over recommended operating range from $T_{AI} = -40^{\circ}C$ to $+85^{\circ}C$, $V_{CC} = +1.7V$ to +5.5V, CL = 1 TTL Gate and 100 pF (unless otherwise noted)

		1.7, 2.5, 2.7		5.0-volt		
Symbol	Parameter	Min	Max	Min	Max	Units
f _{SCL}	Clock Frequency, SCL		400		1000	kHz
t _{LOW}	Clock Pulse Width Low	1.2		0.4		μs
t _{HIGH}	Clock Pulse Width High	0.6		0.4		μs
t _l	Noise Suppression Time		50		40	ns
t _{AA}	Clock Low to Data Out Valid	0.1	0.9	0.05	0.55	μs
t _{BUF}	Time the bus must be free before a new transmission can start	1.2		0.5		μs

Table 2-3.AC Characteristics

Applicable over recommended operating range from $T_{AI} = -40^{\circ}C$ to $+85^{\circ}C$, $V_{CC} = +1.7V$ to +5.5V, CL = 1 TTL Gate and 100 pF (unless otherwise noted)

		1.7, 2	1.7, 2.5, 2.7		5.0-volt		
Symbol	Parameter	Min	Max	Min	Мах	Units	
t _{HD.STA}	Start Hold Time	0.6		0.25		μs	
t _{SU.STA}	Start Setup Time	0.6		0.25		μs	
t _{HD.DAT}	Data In Hold Time	0		0		μs	
t _{SU.DAT}	Data In Setup Time	100		100		ns	
t _R	Inputs Rise Time ⁽¹⁾		0.3		0.3	μs	
t _F	Inputs Fall Time ⁽¹⁾		300		100	ns	
t _{SU.STO}	Stop Setup Time	0.6		.25		μs	
t _{DH}	Data Out Hold Time	50		50		ns	
t _{WR}	Write Cycle Time		5		5	ms	
Endurance ⁽¹⁾	5.0V, 25°C, Byte Mode		1	Million	•	Write Cycles	

Note: 1. This parameter is ensured by characterization only.





3. Device Operation

CLOCK and DATA TRANSITIONS: The SDA pin is normally pulled high with an external device. Data on the SDA pin may change only during SCL low time periods (see Figure 5-2 on page 8). Data changes during SCL high periods will indicate a start or stop condition as defined below.

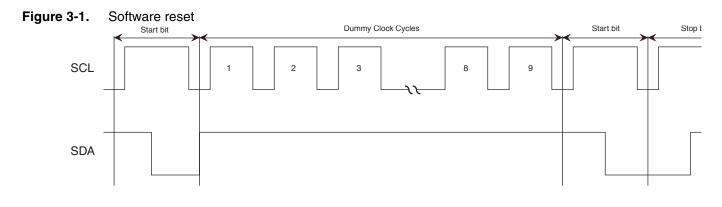
START CONDITION: A high-to-low transition of SDA with SCL high is a start condition which must precede any other command (see Figure 5-3 on page 8).

STOP CONDITION: A low-to-high transition of SDA with SCL high is a stop condition. After a read sequence, the stop command will place the EEPROM in a standby power mode (see Figure 5-3 on page 8).

ACKNOWLEDGE: All addresses and data words are serially transmitted to and from the EEPROM in 8-bit words. The EEPROM sends a zero to acknowledge that it has received each word. This happens during the ninth clock cycle.

STANDBY MODE: The AT24C02C features a low-power standby mode which is enabled: (a) upon power-up and (b) after the receipt of the STOP bit and the completion of any internal operations.

2-Wire Software Reset: After an interruption in protocol, power loss or system reset, any 2-wire part can be reset by following these steps: (a) Create a start bit condition, (b) clock 9 cycles, (c) create another start bit followed by stop bit condition as shown below. The device is ready for next communication after above steps have been completed.



4. Bus Timing

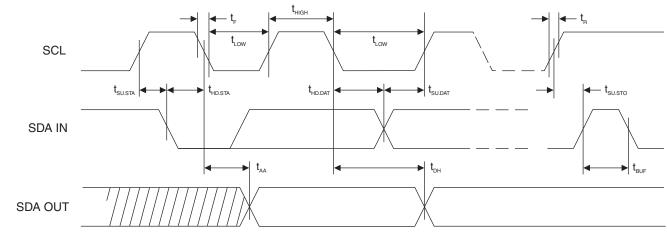
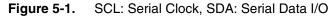
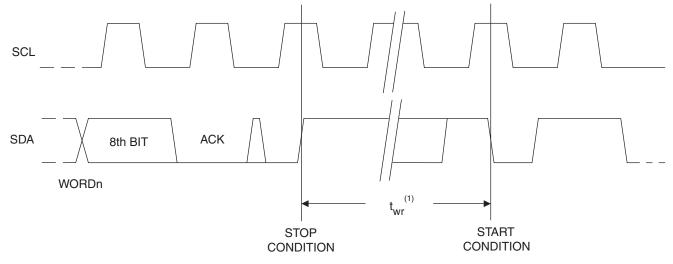


Figure 4-1. SCL: Serial Clock, SDA: Serial Data I/O®

5. Write Cycle Timing





Note: 1. The write cycle time t_{WR} is the time from a valid stop condition of a write sequence to the end of the internal clear/write cycle.







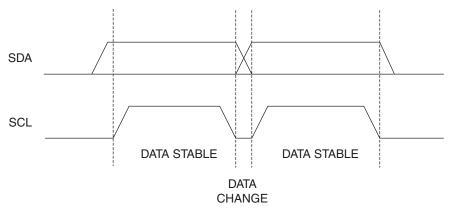
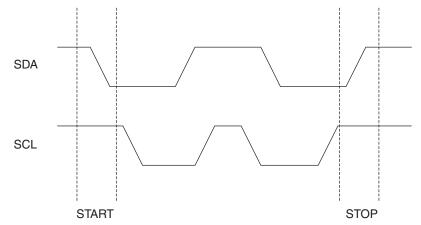
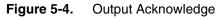
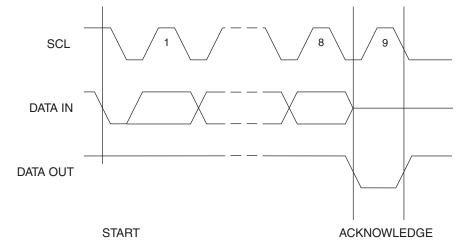


Figure 5-3. Start and Stop Definition







6. Device Addressing

The 2K EEPROM device requires an 8-bit device address word following a start condition to enable the chip for a read or write operation (refer to Figure 8-1).

The device address word consists of a mandatory one, zero sequence for the first four most significant bits as shown. This is common to all the EEPROM devices.

The next 3 bits are the A2, A1 and A0 device address bits for the 2K EEPROM. These 3 bits must compare to their corresponding hard-wired input pins.

The eighth bit of the device address is the read/write operation select bit. A read operation is initiated if this bit is high and a write operation is initiated if this bit is low.

Upon a compare of the device address, the EEPROM will output a zero. If a compare is not made, the chip will return to a standby state.

7. Write Operations

BYTE WRITE: A write operation requires an 8-bit data word address following the device address word and acknowledgment. Upon receipt of this address, the EEPROM will again respond with a zero and then clock in the first 8-bit data word. Following receipt of the 8-bit data word, the EEPROM will output a zero and the addressing device, such as a microcontroller, must terminate the write sequence with a stop condition. At this time the EEPROM enters an internally timed write cycle, t_{WR} , to the nonvolatile memory. All inputs are disabled during this write cycle and the EEPROM will not respond until the write is complete (see Figure 8-2 on page 11).

PAGE WRITE: The 2K EEPROM is capable of an 8-byte page write.

A page write is initiated the same as a byte write, but the microcontroller does not send a stop condition after the first data word is clocked in. Instead, after the EEPROM acknowledges receipt of the first data word, the microcontroller can transmit up to seven data words. The EEPROM will respond with a zero after each data word received. The microcontroller must terminate the page write sequence with a stop condition (see Figure 8-3 on page 11).

The data word address lower three bits are internally incremented following the receipt of each data word. The higher data word address bits are not incremented, retaining the memory page row location. When the word address, internally generated, reaches the page boundary, the following byte is placed at the beginning of the same page. If more than eight data words are transmitted to the EEPROM, the data word address will "roll over" and previous data will be overwritten.

ACKNOWLEDGE POLLING: Once the internally timed write cycle has started and the EEPROM inputs are disabled, acknowledge polling can be initiated. This involves sending a start condition followed by the device address word. The read/write bit is representative of the operation desired. Only if the internal write cycle has completed will the EEPROM respond with a zero allowing the read or write sequence to continue.





8. Read Operations

Read operations are initiated the same way as write operations with the exception that the read/write select bit in the device address word is set to one. There are three read operations: current address read, random address read and sequential read.

CURRENT ADDRESS READ: The internal data word address counter maintains the last address accessed during the last read or write operation, incremented by one. This address stays valid between operations as long as the chip power is maintained. The address "roll over" during read is from the last byte of the last memory page to the first byte of the first page. The address "roll over" during write is from the last byte of the current page to the first byte of the same page.

Once the device address with the read/write select bit set to one is clocked in and acknowledged by the EEPROM, the current address data word is serially clocked out. The microcontroller does not respond with an input zero but does generate a following stop condition (see Figure 8-4 on page 11).

RANDOM READ: A random read requires a "dummy" byte write sequence to load in the data word address. Once the device address word and data word address are clocked in and acknowledged by the EEPROM, the microcontroller must generate another start condition. The microcontroller now initiates a current address read by sending a device address with the read/write select bit high. The EEPROM acknowledges the device address and serially clocks out the data word. The microcontroller does not respond with a zero but does generate a following stop condition (see Figure 8-5 on page 12).

SEQUENTIAL READ: Sequential reads are initiated by either a current address read or a random address read. After the microcontroller receives a data word, it responds with an acknowledge. As long as the EEPROM receives an acknowledge, it will continue to increment the data word address and serially clock out sequential data words. When the memory address limit is reached, the data word address will "roll over" and the sequential read will continue. The sequential read operation is terminated when the microcontroller does not respond with a zero but does generate a following stop condition (see Figure 8-6 on page 12).

Figure 8-1. Device Address

2K	1	0	1	0	A_2	A_1	A ₀	R/W	
	MSE	3						LSB	

Figure 8-2. Byte Write

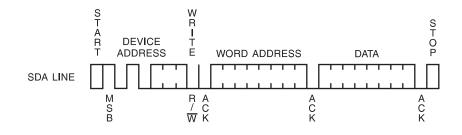


Figure 8-3. Page Write

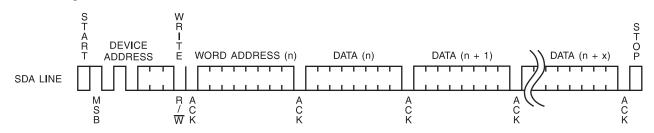


Figure 8-4. Current Address Read

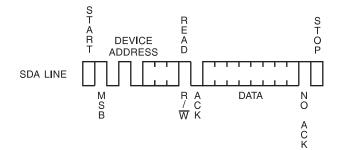
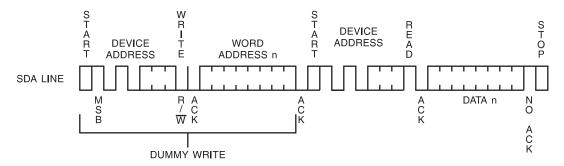
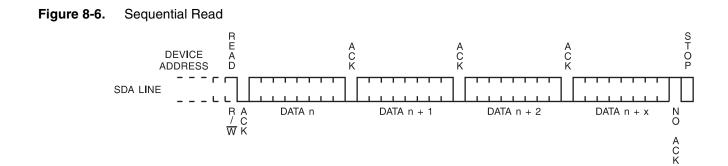




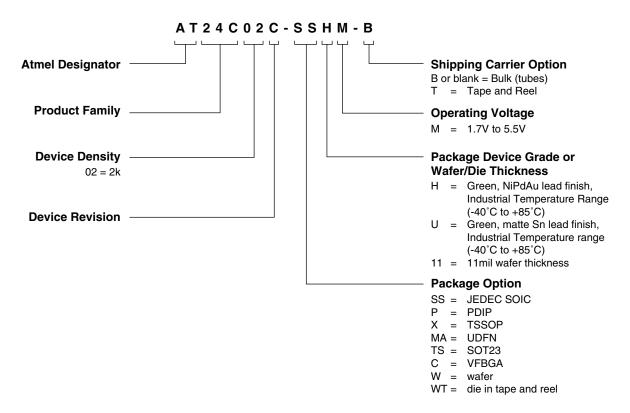


Figure 8-5. Random Read





9. AT24C02C Catalog Numbering Scheme







AT24C02C Ordering Information

Ordering Code	Voltage	Package	Operation Range
AT24C02C-PUM (Bulk form only)	1.7V to 5.5V	8P3	
AT24C02C-SSHM-B ⁽¹⁾ (NiPdAu Lead Finish)	1.7V to 5.5V	8S1	
AT24C02C-SSHM-T ⁽²⁾ (NiPdAu Lead Finish)	1.7V to 5.5V	8S1	
AT24C02C-XHM-T ⁽²⁾ (NiPdAu Lead Finish)	1.7V to 5.5V	8A2	Lead-free/Halogen-free/ Industrial Temperature
AT24C02C-XHM-B ⁽¹⁾ (NiPdAu Lead Finish)	1.7V to 5.5V	8A2	(-40°C to 85°C)
AT24C02CY6-MAHM-T ⁽²⁾ (NiPdAu Lead Finish)	1.7V to 5.5V	8Y6	(
AT24C02C-TSUM-T ⁽²⁾	1.7V to 5.5V	5TS1	
AT24C02CU3-CUM-T ⁽²⁾	1.7V to 5.5V	8U3-1	
AT24C02C-W-11M ⁽³⁾	1.7V to 5.5V	Die Sale	Industrial Temperature (-40°C to 85°C)

Notes: 1. "-B" denotes bulk.

2. "-T" denotes tape and reel. SOIC = 4K per reel. TSSOP, UDFN, SOT23, and VFBGA = 5K per reel.

3. Available in tape and reel and wafer form; order as SL788 for inkless wafer form. Please contact Serial Interface Marketing.

	Package Type						
8P3	8-lead, 0.300" Wide, Plastic Dual Inline Package (PDIP)						
8S1	8-lead, 0.150" Wide, Plastic Gull Wing Small Outline (JEDEC SOIC)						
8A2	8-lead, 4.4 mm Body, Plastic Thin Shrink Small Outline Package (TSSOP)						
8Y6	8-lead, 2.00 mm x 3.00 mm Body, 0.50 mm Pitch, Dual No Lead Package (UDFN)						
5TS1	5-lead, 2.90 mm x 1.60 mm Body, Plastic Thin Shrink Small Outline Package (SOT23)						
8U3-1	8-ball, die Ball Grid Array Package (VFBGA)						

10. Part Marking Scheme

<u>8-PDIP</u>

Seal Year

WW = Seal Week

02C = Device

M = Voltage Indicator

*Lot Number to Use ALL Characters in Marking

BOTTOM MARK No Bottom Mark





8-SOIC

Seal Year

101	MARI	-						Week
		 T						 W
				_		_		
	Ũ	2	•		M			·
	*		: Nur					
	Pin 1 Indicator (Dot)							
H = Material Set								
Y = \$	Y = Seal Year							
WW = Seal Week								
02C = Device								
M =	M = Voltage Indicator							

*Lot Number to Use ALL Characters in Marking

BOTTOM MARK

No Bottom Mark

8-TSSOP

TOP MARK

Pin 1 Indicator (Dot) | |---|---|---| * H Y W W |---|---|---| 0 2 C M |---|---|---|

H = Material Set

Y = Seal Year

WW = Seal Week

02C = Device

M = Voltage Indicator

```
BOTTOM MARK

|---|---|---|---|---|

X X

|---|---|---|---|---|---|

A A A A A A A

|---|---|---|---|---|

<- Pin 1 Indicator

Lot Number
```

XX = Country of Origin

AAAAAA = Lot Number





<u>SOT23</u>

TOP MARK

2C = Device

M = Voltage Indicator

W = Write Protect Feature

U = Material Set

Pin 1 Indicator (Dot)

BOTTOM MARK

|---|---|---| Y M T C |---|---|---|

Y = One Digit Year Code

M = Seal Month

TC = Trace Code

<u>UDFN</u>

TOP MARK

$$|---|---|---|0 2 C|---|---|---|H M|---|---|---|Y T C|---|---|---|*02C = DeviceH = Material SetM = Voltage Indicator$$

Y = Year of Assembly

TC = Trace Code

Pin 1 Indicator (Dot)

<u>VFBGA</u>

TOP MARK

LINE 1-----> 02CU LINE 2----> YMTC |<-- Pin 1 This Corner

02C = Device

U = Material Set

Y = One Digit Year Code

M = Seal Month

TC = Trace Code



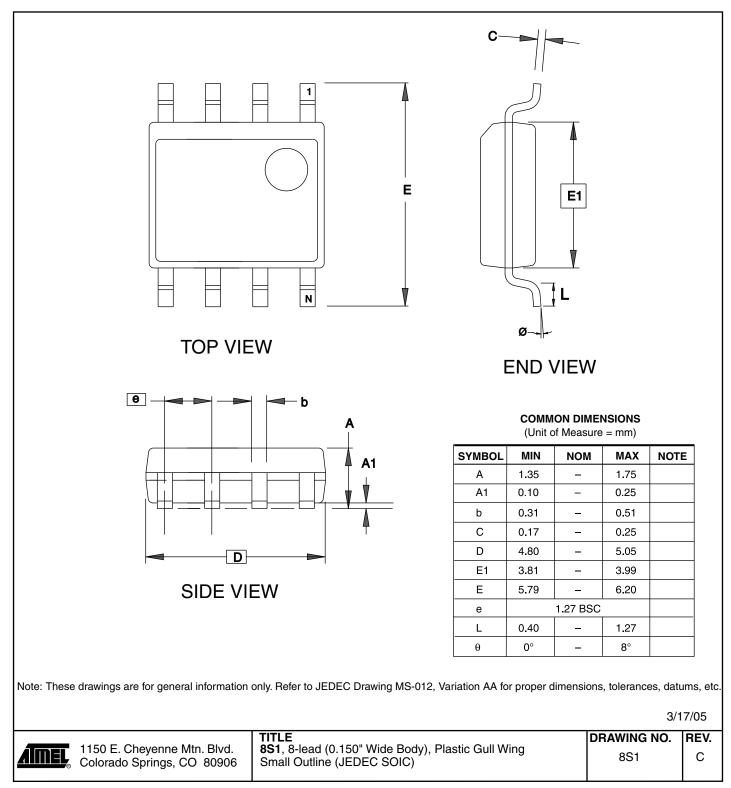


11. Packaging Information

8P3 – PDIP

²⁰ AT24C02C [Preliminary]

8S1 – JEDEC SOIC

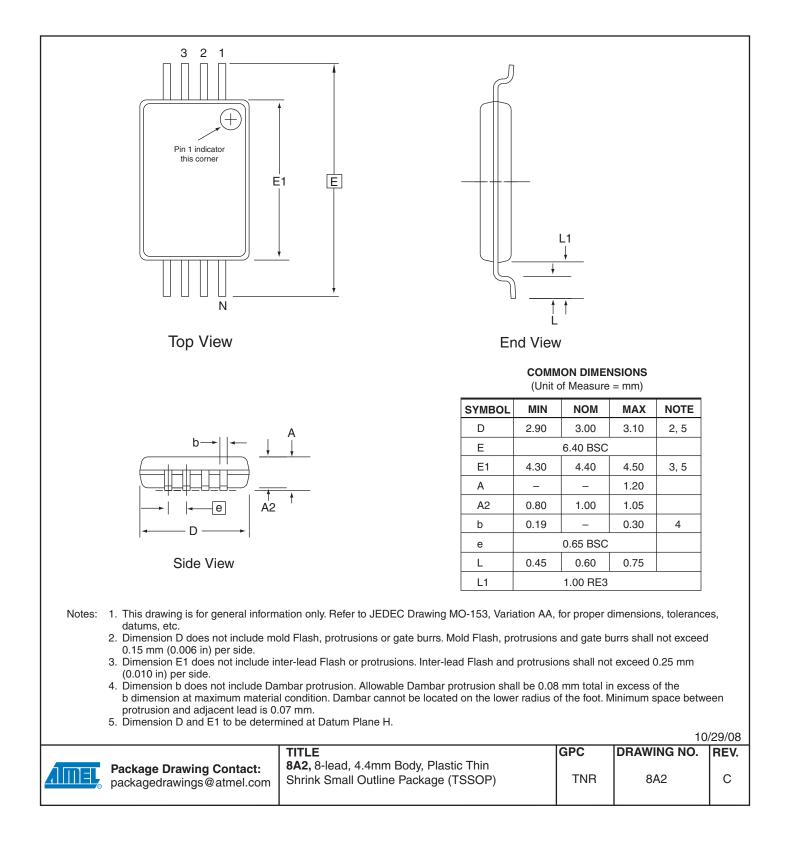




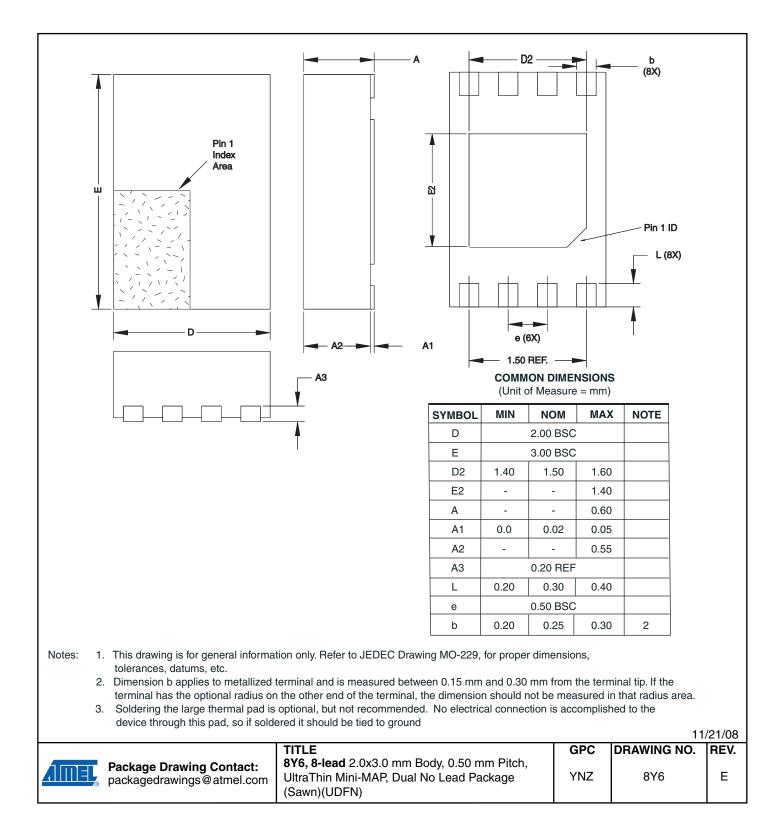
8700B-DEEPR-2/10



8A2 – TSSOP



8Y6 - UDFN

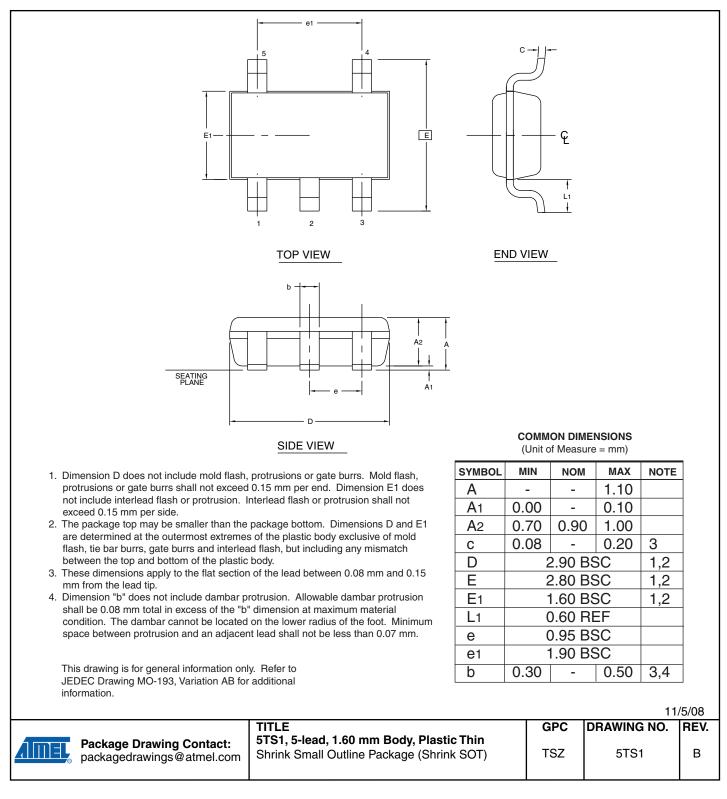




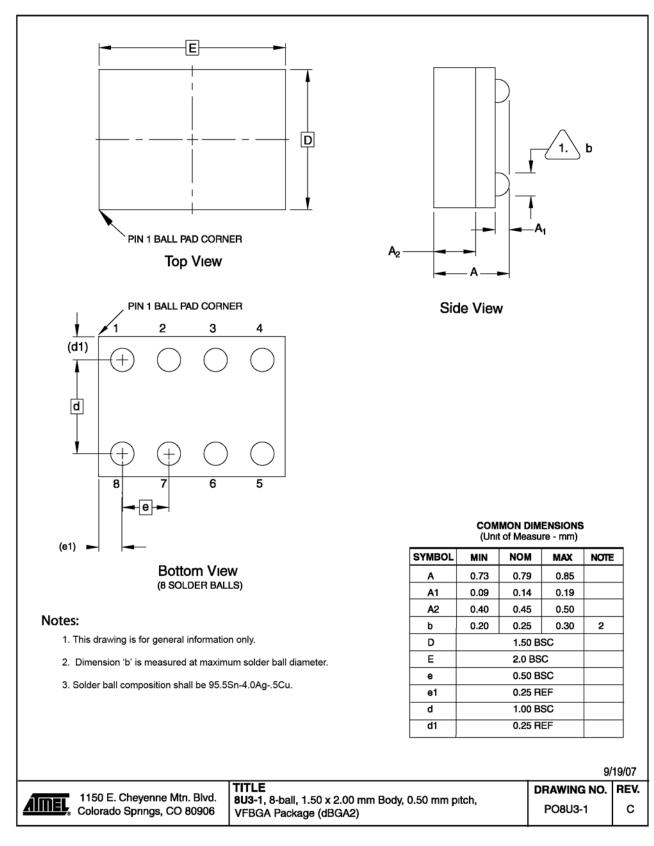
8700B-DEEPR-2/10



5TS1 - SOT23



8U3-1 - VFBGA





8700B-DEEPR-2/10



12. Revision History

Doc. Rev. Date Comments		Comments
8700B	02/2010	Corrected Catalog Numbering Scheme and Ordering Information
8700A	12/2009	Initial Document Release



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